

Search Notes**Application/Control No.**

10/540,238

Examiner

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Applicant(s)/Patent under Reexamination

MIKADO ET AL.

Art Unit

2856

SEARCHED

Class	Subclass	Date	Examiner
73	514.34	4/26/2006	HK
73	514.29	4/26/2006	HK
73	514.16	4/26/2006	HK
73	514.33	4/26/2006	HK
310	329-332	4/26/2006	HK
310	311	4/26/2006	HK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner